Amendments to the Specification and Abstract

In the Specification:

Please replace paragraph [0001] with the following rewritten paragraph:

[0001] The present invention relates to a method and a system for the non-instrument-dependent determination of the coordinates of a point imaged using a microscope, and a calibration slide for use therefor. ~~Microscopes are frequently used for detecting small structures which cannot be made out with the naked eye and for discovering characteristic features in such structures. A fundamental use for microscopy in cytology, histology and pathology is for reviewing a specimen and looking for structures, cells or combinations of cells and the like which are of interest. If the sites of these structures are found on the specimen, it is desirable to note them, for a variety of reasons. For example, the structure found has to be located again at a later stage by the same or a different user for checking, for further inspection or for quality control. For this purpose, many microscopes have a unit for determining the coordinates of positions of a point in an instrument-dependent system of coordinates. By electromechanically determining these coordinates, it is possible to return to the location discovered at a later stage.~~

Before paragraph [0002] please insert the heading --BACKGROUND-- and new paragraph [0001.1] as follows:

--[0001.1] Microscopes are frequently used for detecting small structures which cannot be made out with the naked eye and for discovering characteristic features in such structures. A fundamental use for microscopy in cytology, histology and pathology is for reviewing a specimen and looking for structures, cells or combinations of cells and the like which are of interest. If the sites of these structures are found on the specimen, it is desirable to note them, for a variety of reasons. For example, the structure found has to be located again at a later stage by the same or a different user for checking, for further inspection or for quality control. For this purpose, many microscopes have a unit for determining the coordinates of positions of a point in an instrument-dependent system of coordinates. By electromechanically determining these

coordinates, it is possible to return to the location discovered at a later stage.--

Before paragraph [0003] please insert the heading
--SUMMARY OF THE INVENTION--.

Please replace paragraph [0004] with the following rewritten paragraph:
[0004] ~~This problem is solved by~~ The present invention provides a method and system according to the invention for non-instrument-dependent determination of coordinates of a point imaged using a microscope. The method according to the invention envisages that first of all, at given object-related reference coordinates (X_1, Y_1, Z_1) of at least one reference point E_1 in a DICOM coordinate system, the relevant instrument coordinates (x_1, y_1, z_1) of the minimum of one imaged reference point E_1 in an instrument-dependent coordinate system are determined and from them a transformation rule Φ for converting instrument-dependent coordinates (x, y, z) into the coordinates (X, Y, Z) of the DICOM coordinate system is obtained. Then, for non-instrument-dependent coordinate determination, the instrument coordinates (x_p, y_p, z_p) of an imaged point P are converted by means of the transformation rule Φ discovered into non-instrument-dependent coordinates (X_p, Y_p, Z_p) of the DICOM coordinate system.

Before paragraph [0022], please insert the heading --BRIEF DESCRIPTION OF THE DRAWINGS--.

Before paragraph [0027], please insert the heading --DETAILED DESCRIPTION--.